

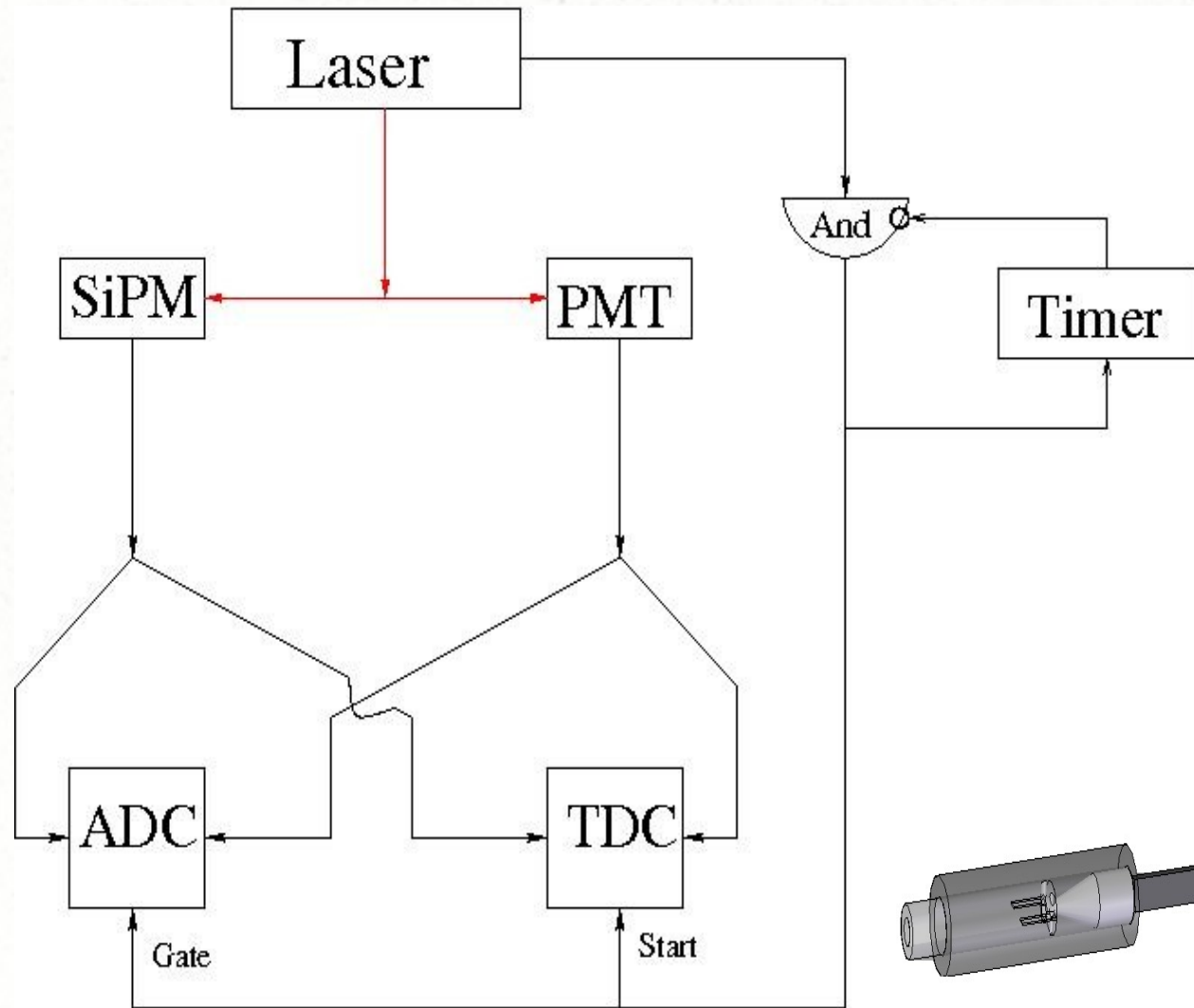
SiPM Bias Analysis

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On behalf of UofR group
September 11, 2012

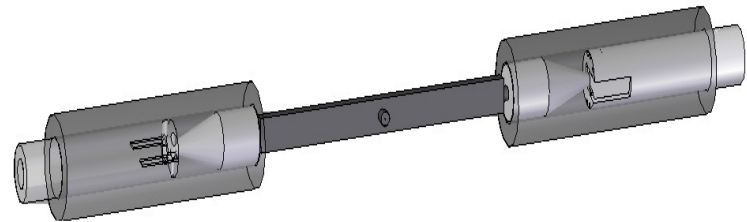
Motivation

- In response to the theoretical results achieved by Yi Qiang on July 24, 2012
- To perform a direct check of the response of the 2010 SiPMs to varying voltage biases
- To provide a physical analysis of the normalized resolution and dark current of the 2010 SiPMs

Experimental Setup



- PicoQuant PDL 800-B laser
- 2.5 MHz frequency pulses
- 2 ms timer to slow count rate
- Bias supplied by Keithley 6487 Voltage Source



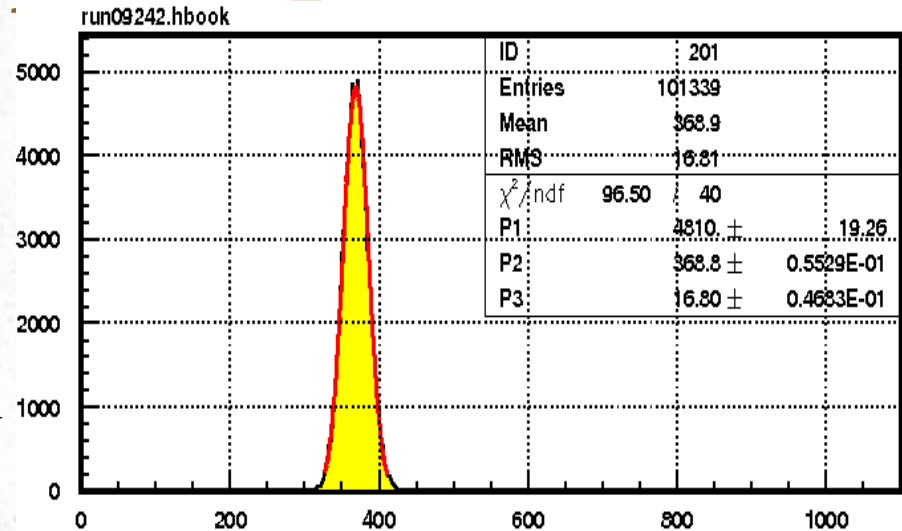
Data Sets

- Signal Data:
 - Taken at laser intensity 2.2, 2.4, and 2.6 (a.u.)
 - Using amplifier, bias, and laser light
- Noise:
 - Using amplifier and bias. No laser light.
- 50 Ω pedestal
 - Taken with 50 Ω terminators in ADC inputs

Spectra Examples

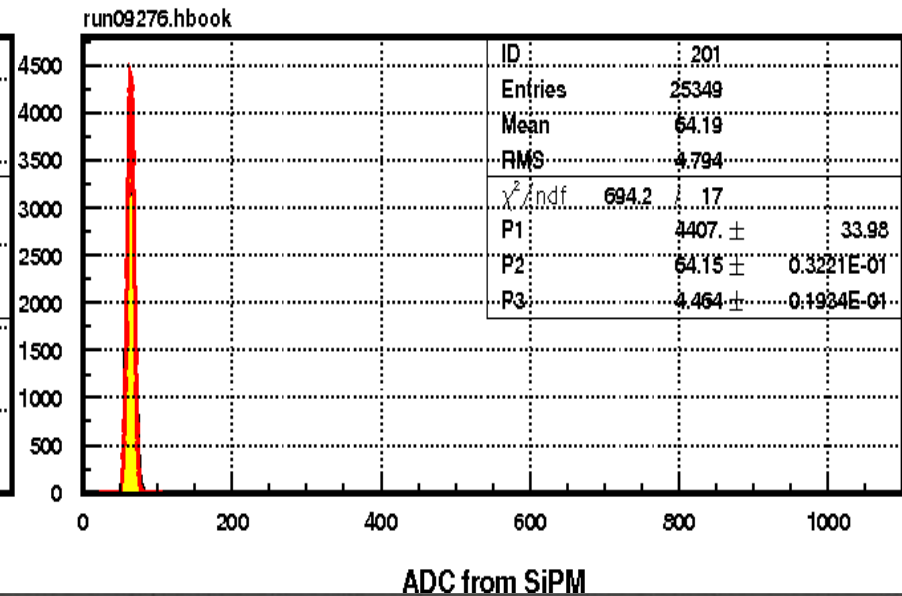
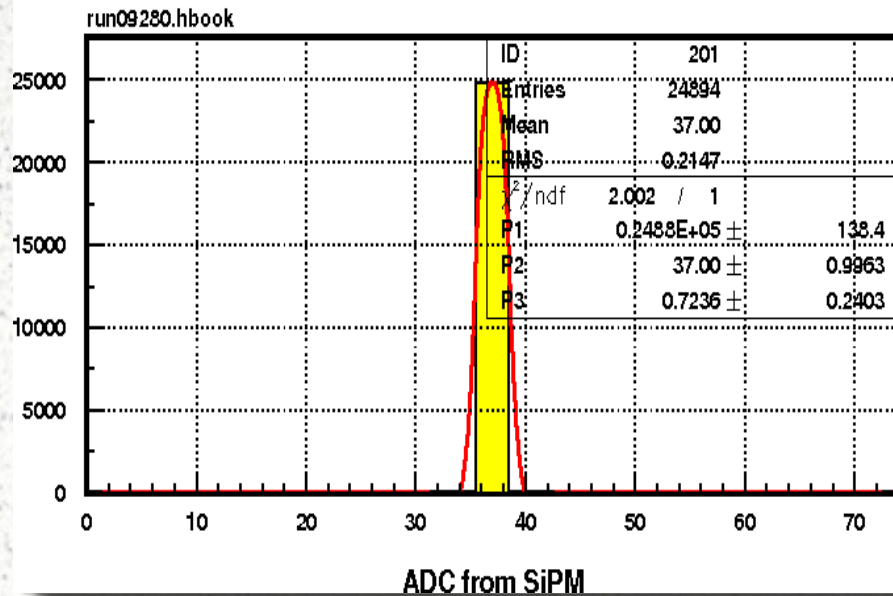
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- Top Right: Signal Spectrum
- Bottom Left: 50 Ω pedestal
- Bottom Right: Noise Spectrum



2012/08/23

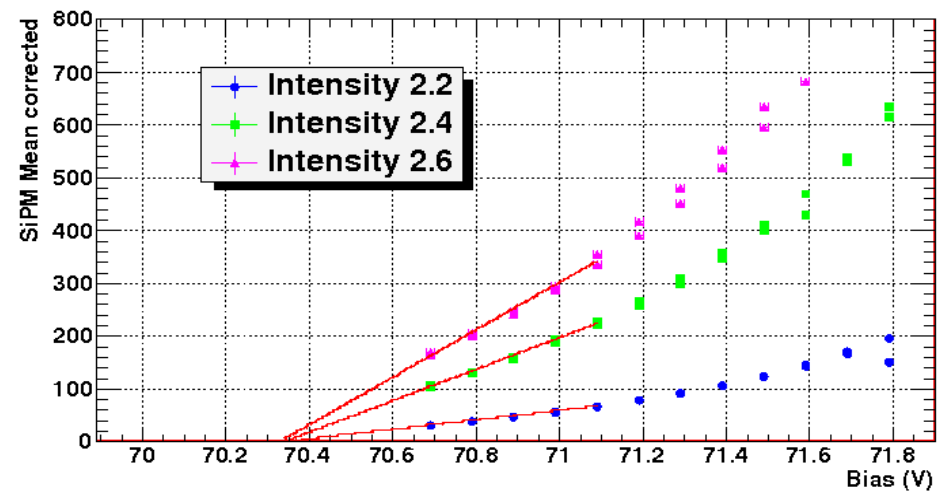
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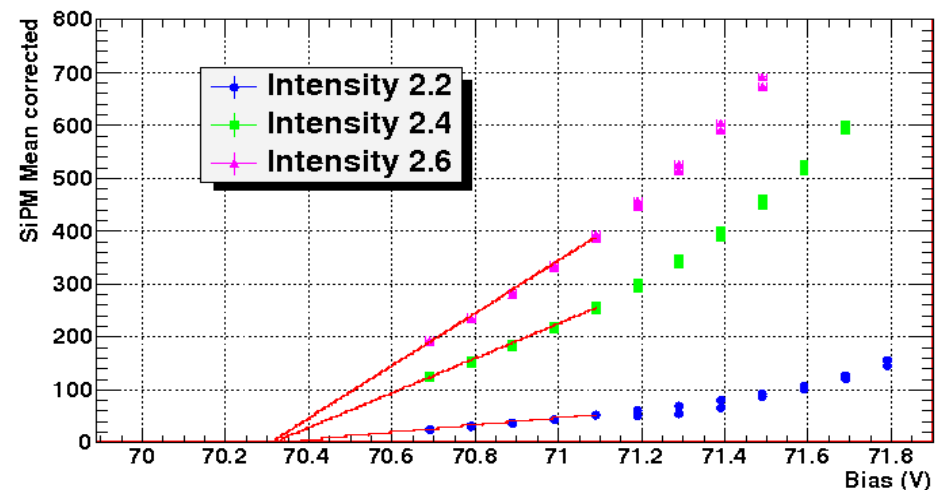
Breakdown Voltage

- Determined the breakdown voltage of the 2010 pre-production SiPMs was 0.4 V higher than stated from Jlab.
- New breakdown voltage found to be 70.34 ± 0.02 V
- Adjusted all further graphs to account for adjusted breakdown voltage.

SiPM 10 Crossing points



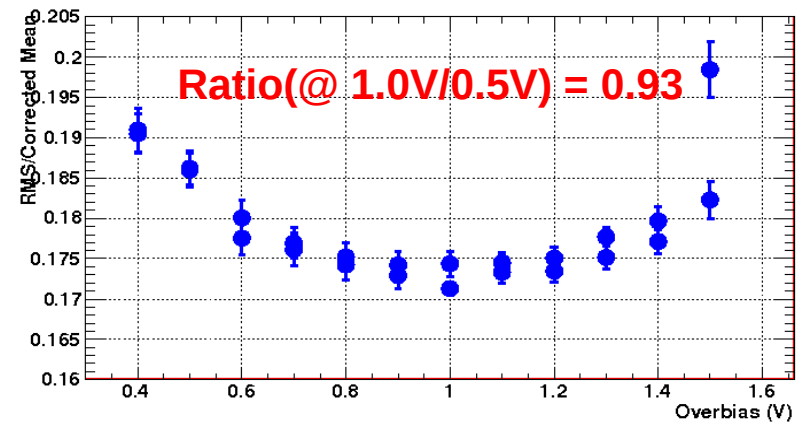
SiPM 2 Crossing points



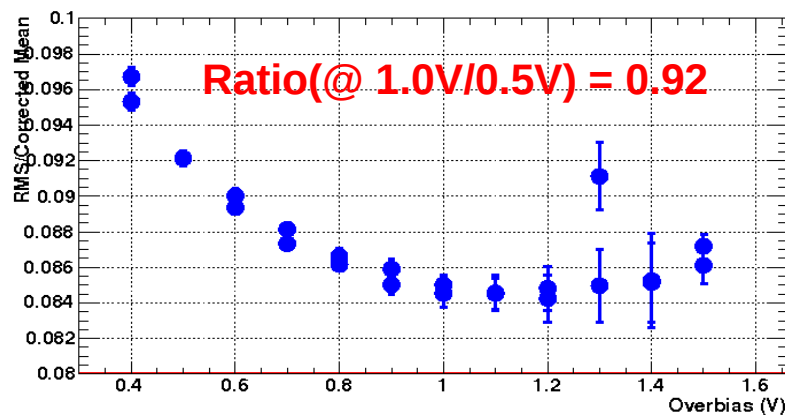
Normalized Resolution: SiPM 10

- Plot of RMS/Corrected Mean vs bias
- Top Right: Laser Intensity 2.2
- Bottom Left: Laser Intensity 2.4
- Bottom Right: Laser Intensity 2.6

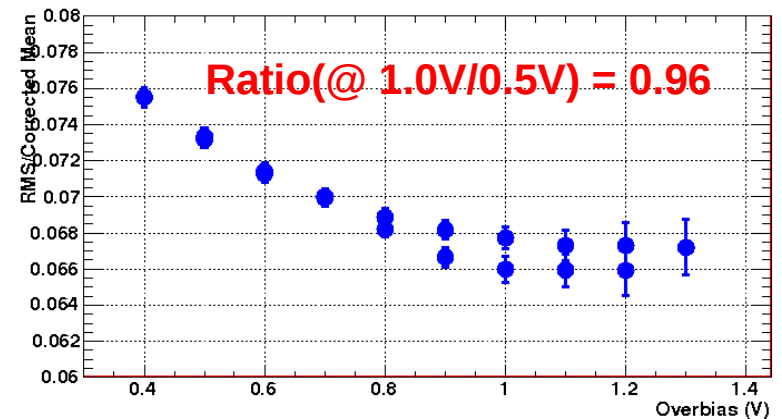
Normalized Resolution SiPM 10: Laser Intensity 2.2



Normalized Resolution SiPM 10: Laser Intensity 2.4



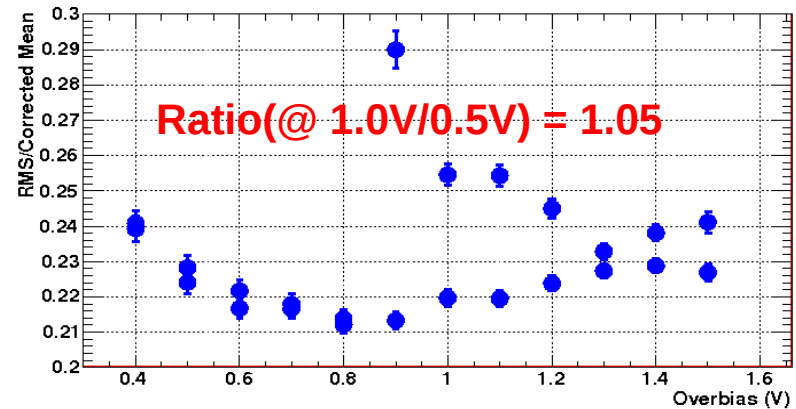
Normalized Resolution SiPM 10: Laser Intensity 2.6



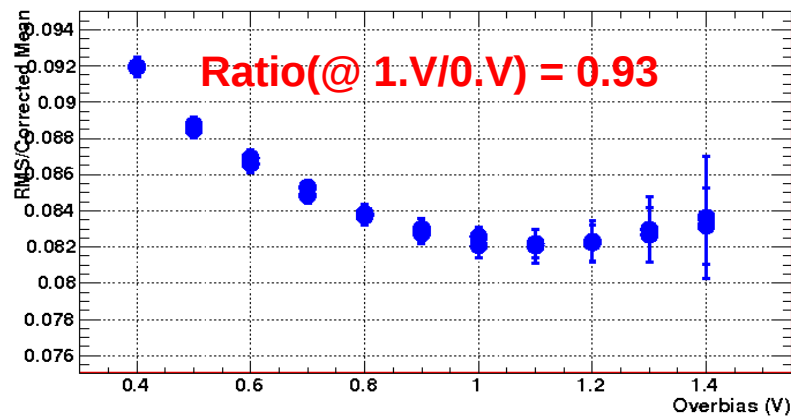
Normalized Resolution: SiPM 2

- Plot of RMS/Corrected Mean vs bias
- Top Right: Laser Intensity 2.2
- Bottom Left: Laser Intensity 2.4
- Bottom Right: Laser Intensity 2.6

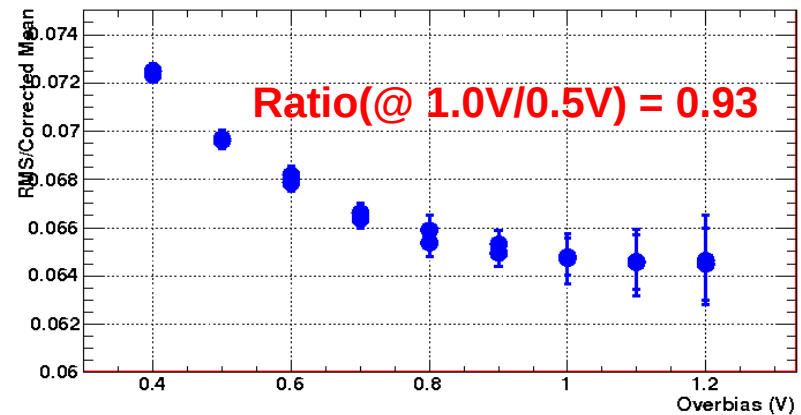
Normalized Resolution SiPM 10: Laser Intensity 2.2



Normalized Resolution SiPM 10: Laser Intensity 2.4

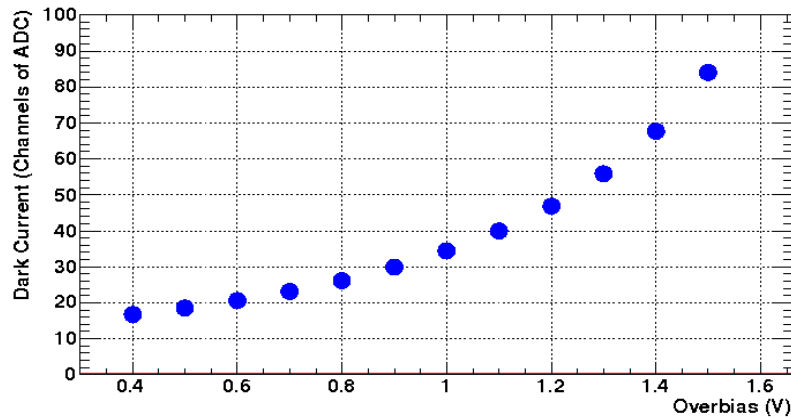


Normalized Resolution SiPM 10: Laser Intensity 2.6

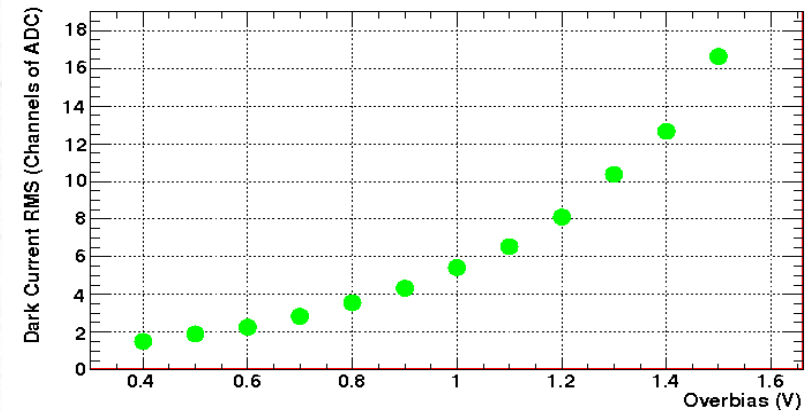


SiPM 10: Mean Noise and RMS

SiPM 10: Average Noise

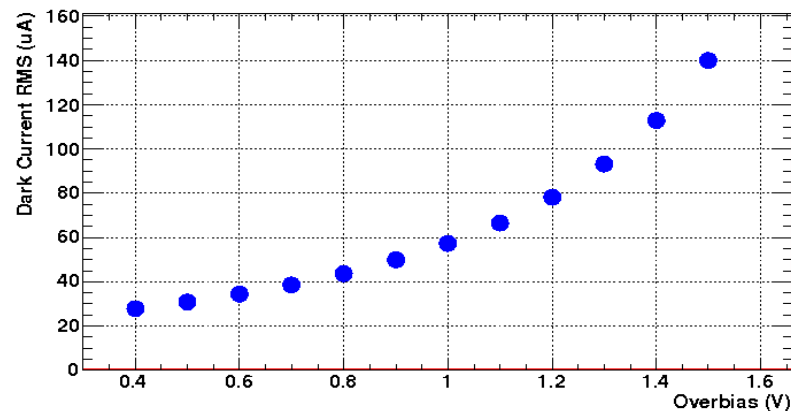


SiPM 10: Average Noise RMS

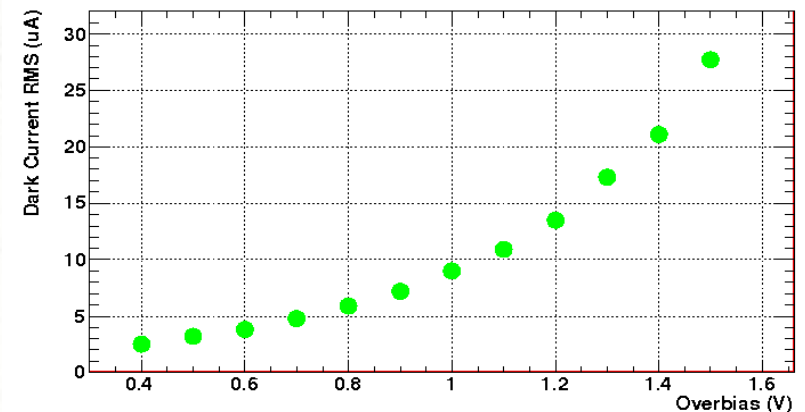


- Top: Average noise and RMS in ADC channels
- Bottom: Average noise and RMS expressed as dark current

SiPM 10: Average Noise

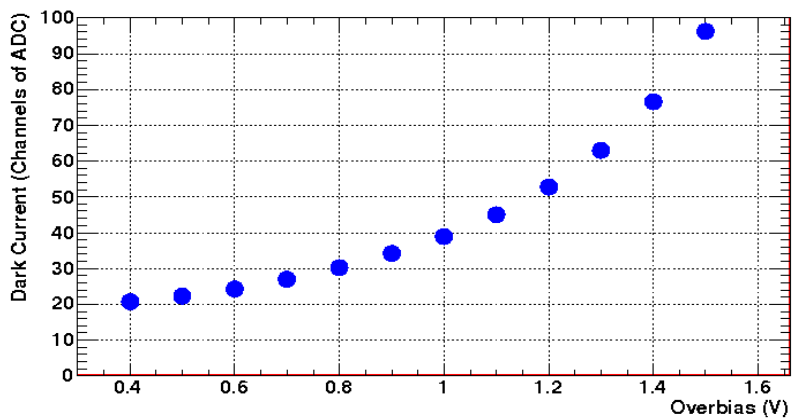


SiPM 10: Average Noise RMS

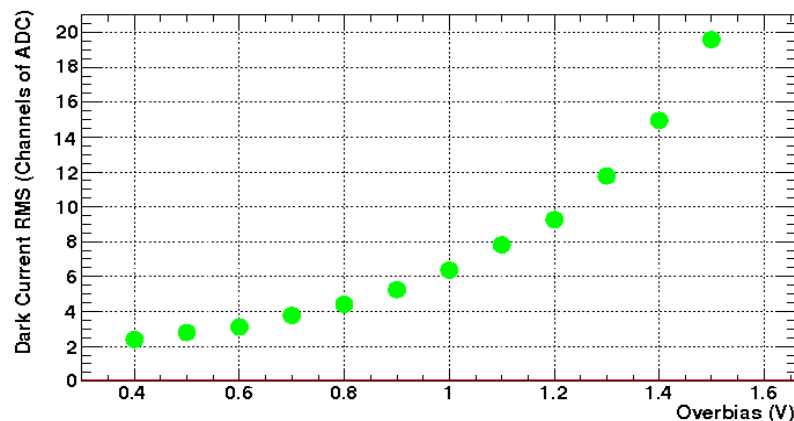


SiPM 2: Mean Noise and RMS

SiPM 2: Average Noise

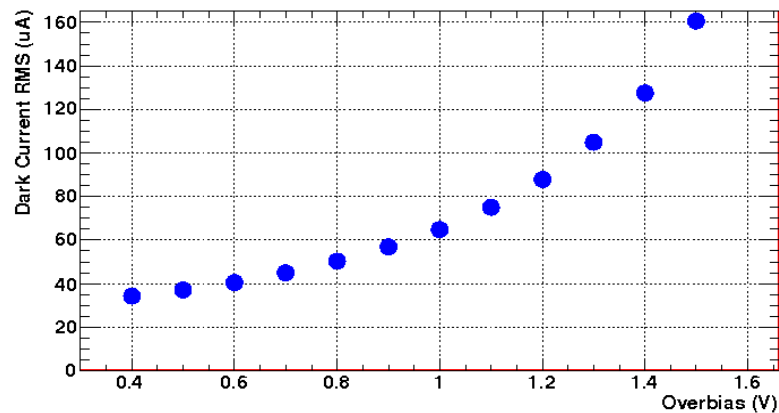


SiPM 2: Average Noise RMS

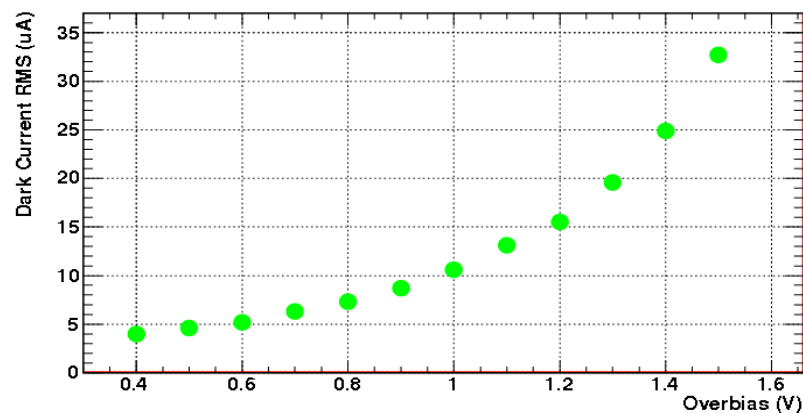


- Top: Average noise and RMS in ADC channels
- Bottom: Average noise and RMS expressed as dark current

SiPM 2: Average Noise

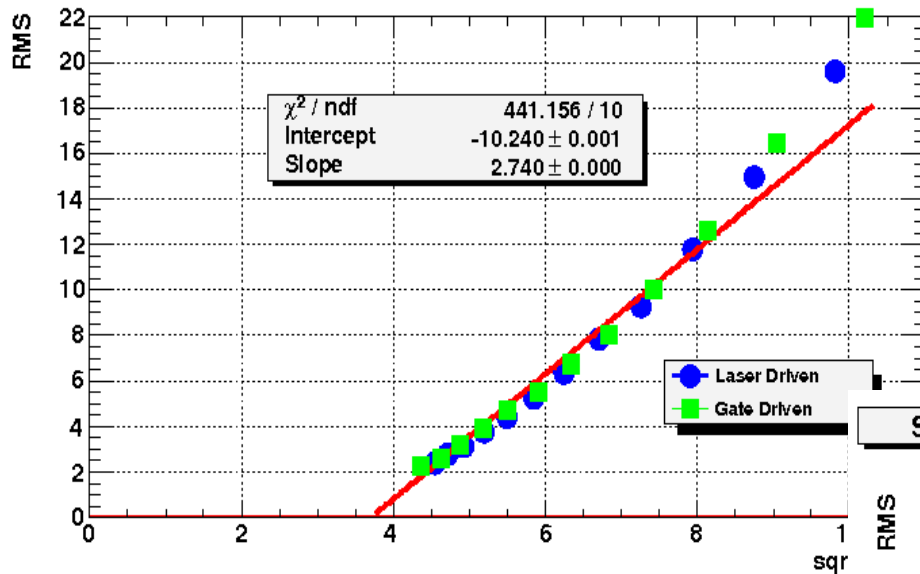


SiPM 2: Average Noise RMS



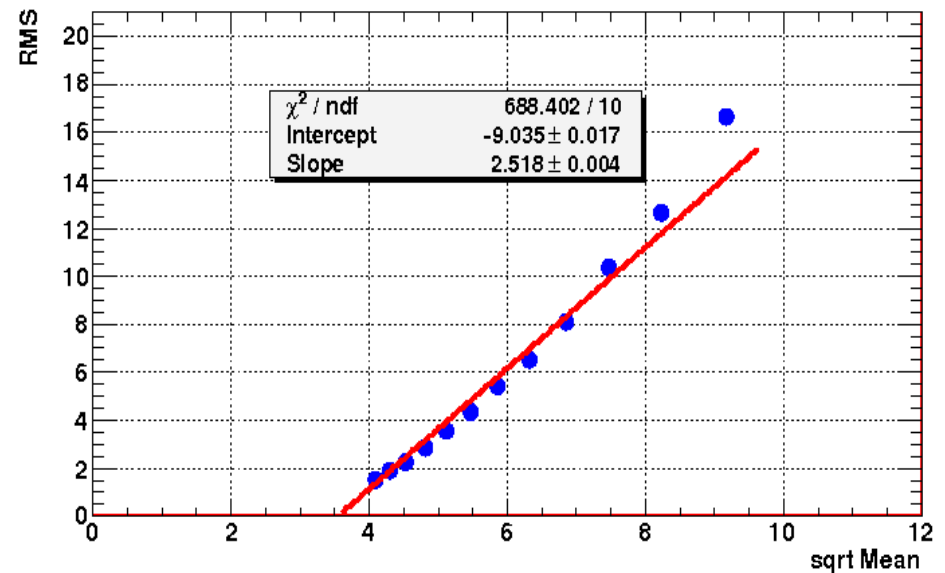
Check for Poisson Characteristics

SiPM 2: Poissonian characteristics - Linear



- RMS vs sqrt Mean of noise
- Fitted with linear line to check on Poisson characteristics
- Does not go through 0,0 or follow data closely.

SiPM 10: Poissonian characteristics - Linear



Conclusions

- Resolution is minimized around 0.9V – 1.1V
 - => 1.2 V may be too high
- 15% increase in noise going from 1.0V to 1.1V
- 35% increase in noise going from 1.0V to 1.2V
- Noise does not follow Poissonian trend
 - => Rises faster than expected
- Future Measurements:
 - Recheck outliers
 - Check 2011 Units